Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/693,896	CHEN ET AL.	
Examiner	Art Unit	_
Stephen W. Smoot	2813	

	SEAR	CHED		
Class	Subclass	Date	Examiner	
438	108	1/27/2005	sws	
438	612	1/27/2005	sws	
438	613	1/27/2005	sws	JEW!
438	614	1/27/2005	sws	
257	738	1/27/2005	sws	
257	E21.508	1/27/2005	sws	
29	842	1/27/2005	sws	
Updated	Above	5/9/2005	sws	J.W.J J.W.Z
438	615	5/9/2005	sws	8.W.R
228	180.22	5/9/2005	sws	1.N.Z.
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INI	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
			00.0	
Same	as Above	5/9/2005	X,W,X sws	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Key Words: Solder Ball, Bump - Flux; Active Surface; Bond Pad; Under Bump Metallurgy;	1/27/2005	IN. sws
Passivation Layer; Solder Reflow; Solid Flux.	1/27/2005	IN.
Updated Above Search	5/9/2005	I.W.S sws
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	1/27/2005 P 5-9-05	sws J.W.J.